F. Silicon and Group-IV Devices and Integration Technology 분과
[FB2-F] Neuromorphic Technology

FB2-F-1 **10:45~11:00**	**Classification Methods Using Additional Output Neurons to Increase Inference Accuracy in Hardware-based Binarized Neural Network** Hyeongsu Kim, Sung-Tae Lee, Dongseok Kwon, Byung-Gook Park, and Jong-Ho Lee *Department of Electrical and Computer Engineering and Inter-University Semiconductor Research Center, Seoul National University*
FB2-F-2 **11:00~11:15**	**Improved Neuron Circuit Using Ni/SiN$_x$/n$^+$-Si RRAM as Synaptic Devices** Yeonwoo Kim, Chae Soo Kim, Myung-Hyun Baek, and Byung-Gook Park *Inter-University Semiconductor Research Center (ISRC) and Department of Electrical and Computer Engineering, Seoul National University*
FB2-F-3 **11:15~11:30**	**Novel NOR Type Synapse Array Using Additional N-well for Weight Update Method** Jonghyuk Park, Myung-Hyun Baek, Suhyeon Kim, Young Suh Song, and Byung-Gook Park *Department of Electrical and Computer Engineering, Seoul National University*
FB2-F-4 **11:30~11:45**	**Investigation on Extremely-thin-body Polysilicon-based Synaptic Transistor** Junsu Yu, Myung-Hyun Baek, Kyung Kyu Min, Kyungchul Park, Young Suh Song, and Byung-Gook Park *Inter-University Semiconductor Research Center (ISRC) and Department of Electrical and Computer Engineering, Seoul National University*
FB2-F-5 **11:45~12:00**	**Relationship Between Threshold Voltage and Membrane Capacitance of Integrate and Fire Neuron in SNN System** Gyuho Yeom, Dongseok Kwon, Min Kyu Park, and Jong-Ho Lee *Department of Electrical and Computer Engineering and Inter-University Semiconductor Research Center, Seoul National University*
FB2-F-6 **12:00~12:15**	**Non-linearity Effect of Current Mirror due to High Fan-in on Spiking Neural Network** Bosung Jeon, Sungmin Hwang, Kyungchul Park, Jong-Ho Lee, and Byung-Gook Park *Department of Electrical and Computer Engineering, Seoul National University*
FB2-F-7 **12:15~12:30**	**Effect of Weight Loss of Synaptic Devices on Inference Accuracy** Ho-Nam Yoo, Hyeong-Su Kim, and Jong-Ho Lee *Inter-University Semiconductor Research Center (ISRC) and Department of Electrical and Computer Engineering (ECE), Seoul National University*